



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: A1403-02R1 DATE: 22-Aug-2014 Product Affected: CABGA-176 Refer to Attachment II for the affected part numbers Date Effective: 30-Sep-2014	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark Lot# will have a <input checked="" type="checkbox"/> Back Mark "A" prefix to denote alternate site, OSE <input type="checkbox"/> Date Code Taiwan <input type="checkbox"/> Other
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Contact: IDT PCN DESK E-mail: pcndesk@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Please contact your local sales representative for sample request & availability.
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DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>Revision 1: This revised notice is to remove some of the affected part# from the PCN and add two affected part#. PCN effective date remains unchanged. Refer to attachment II for the updated affected part#.</p> <p>This notification is to advise our customers that IDT is adding OSE, Taiwan (OSET) as an alternate assembly facilities for CABGA-176 package type.</p> <p>There is no change to the moisture performance.</p> <p>Attachment I details the qualification data for this change</p>
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RELIABILITY/QUALIFICATION SUMMARY:
Refer to qualification data shown in attachment I.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____
CUSTOMER COMMENTS: _____	

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT I - PCN # : A1403-02R1

PCN Type: Manufacturing Site - Alternate Assembly Location

Data Sheet Change: None

No change in moisture sensitivity level (MSL)

Detail Of Change:

This notification is to advise our customers that IDT is adding OSE, Taiwan (OSET) as an alternate assembly facilities for CABGA-176 package type.

Presently, OSET is a qualified IDT subcontractors.

The material sets used at OSET are qualified IDT materials.

There is no change to the moisture performance of this package using the assembly material sets as listed in Table 1.

Table 1: Assembly Material Sets for the Existing Assembly & Alternate Assembly

Material Set / Assembly	Existing Assembly		Alternate Assembly
	ASEK - ASE, Taiwan	CHM - ChipMos, Taiwan	OSET - OSE, Taiwan
Die Attach	Ablestik 2100A	Ablestik 2025D	Henkel 2300
Wire	Au wire	Au wire	Au wire
Mold Compound	KE-G1250LKDS	KE-G1250TC	KE-G1250
Solder Balls	96.5Sn /3.0 Ag /0.5Cu	96.5Sn /3.0 Ag /0.5Cu	96.5Sn /3.0 Ag /0.5Cu



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Qualification Test Plans and Results :

Qual Plan & Results: The qualification was performed in accordance with JEDEC47 recommended tests.

Qual Vehicle: CABGA-176 (4 lots)

Test Description	Test Method	Test Results (Rej / SS)
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0 / 30
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0 / 30
High Temperature Storage Test (150°C, 1000 hours)	JESD22-A103	0 / 30
Moisture Sensitivity Classification (MSL 3, 260 °C)	J-STD-020	0 / 25
Solder Ball Shear Test (1000 Hrs)	JESD22-B117	0 / 5
X-ray Examination	IDT Spec MAC- 3012	0 / 45
External Visual Inspection	JESD22-B101	0 / 25
Internal Visual Inspection	MIL-STD-883 (Method 2010)	0 / 5

Note:

* Test requires moisture pre-conditioning sequence per JESD22-A113 prior to stress test



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Updated Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
SSTE32882KA1AKG	SSTE32882KA1AKGI	SSTE32882KB1AKG	SSTE32882KB1AKGI
SSTE32882KA1AKG8	SSTE32882KA1AKGI8	SSTE32882KB1AKG8	SSTE32882KB1AKGI8
SSTE32882KA1AKG/M	SSTE32882KA1AKG8/M		

Part Numbers Added in PCN Revision 1

Part Number	Part Number
SSTE32882KA1AKG/M	SSTE32882KA1AKG8/M

Part Numbers Removed in PCN Revision 1

Part Number	Part Number	Part Number	Part Number
74SSTE32882AAKG	SSTE32882AAKGT	SSTE32882HLBAKG	SSTE32882KB0AKG8
74SSTE32882AAKG8	SSTE32882AK0AKG	SSTE32882HLBAKG8	SSTE32882T1ZAAKG
74SSTE32882AKG	SSTE32882AK0AKG8	SSTE32882HLBAKGI	SSTE32882T1ZAAKG8
74SSTE32882AKG8	SSTE32882CLA0AKG	SSTE32882HLBAKGI8	SSTE32882T2ZAAKG
74SSTE32882CAKG	SSTE32882CLA0AKG8	SSTE32882HLCAKG	SSTE32882T2ZAAKG8
74SSTE32882CAKG8	SSTE32882CLA1AKG	SSTE32882HLCAKG8	SSTE32882TNA1AKG
74SSTE32882DAKG	SSTE32882CLA1AKG8	SSTE32882HNAAKG	SSTE32882TNA1AKG8
74SSTE32882DAKG8	SSTE32882CLA2AKG	SSTE32882HNAAKG8	SSTE32882TNAAKG
74SSTEF32882AKG	SSTE32882CLA2AKG8	SSTE32882KA0AKG	SSTE32882TNAAKG8
74SSTEF32882AKG8	SSTE32882HLB1AKG	SSTE32882KA0AKG8	
SSTE32882AAKG	SSTE32882HLB1AKG8	SSTE32882KB0AKG	